



Irradiation of Switcher3 and DCDD2



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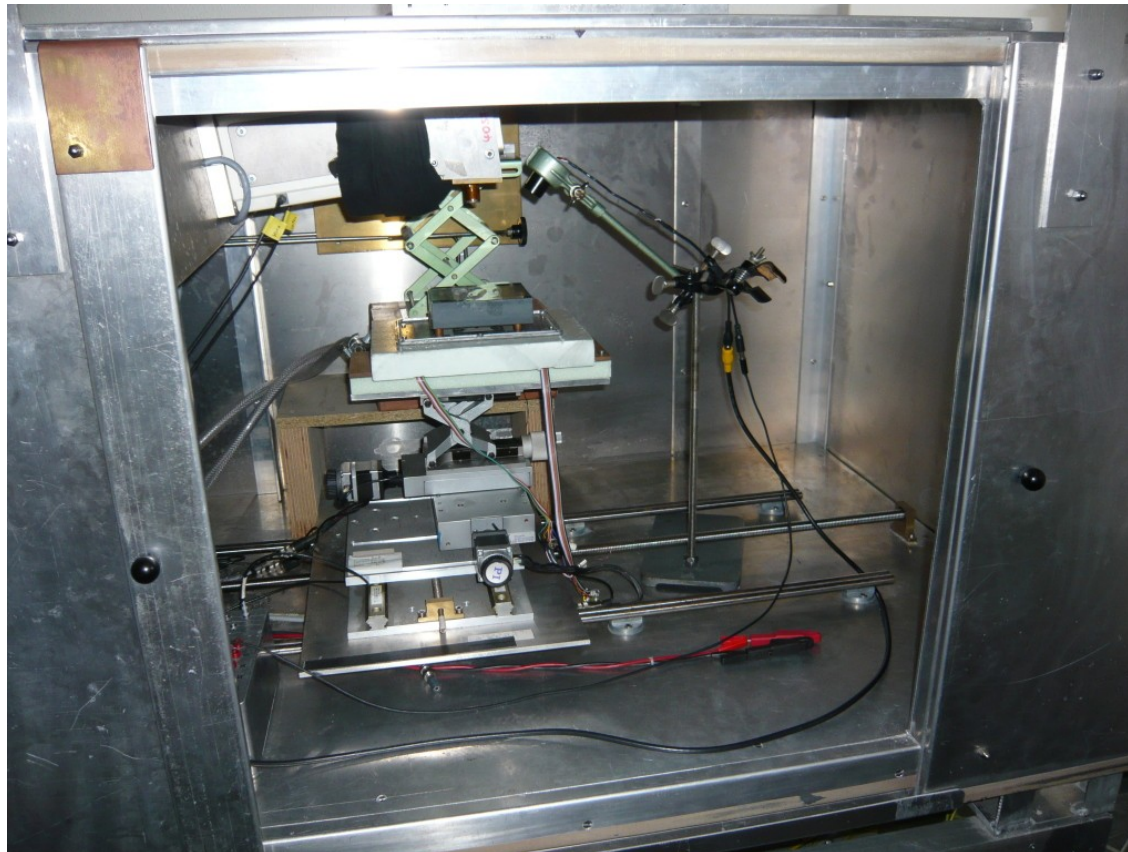
International Workshop on DEPFET detectors and
applications

Heidelberg

10. - 12.09.2008

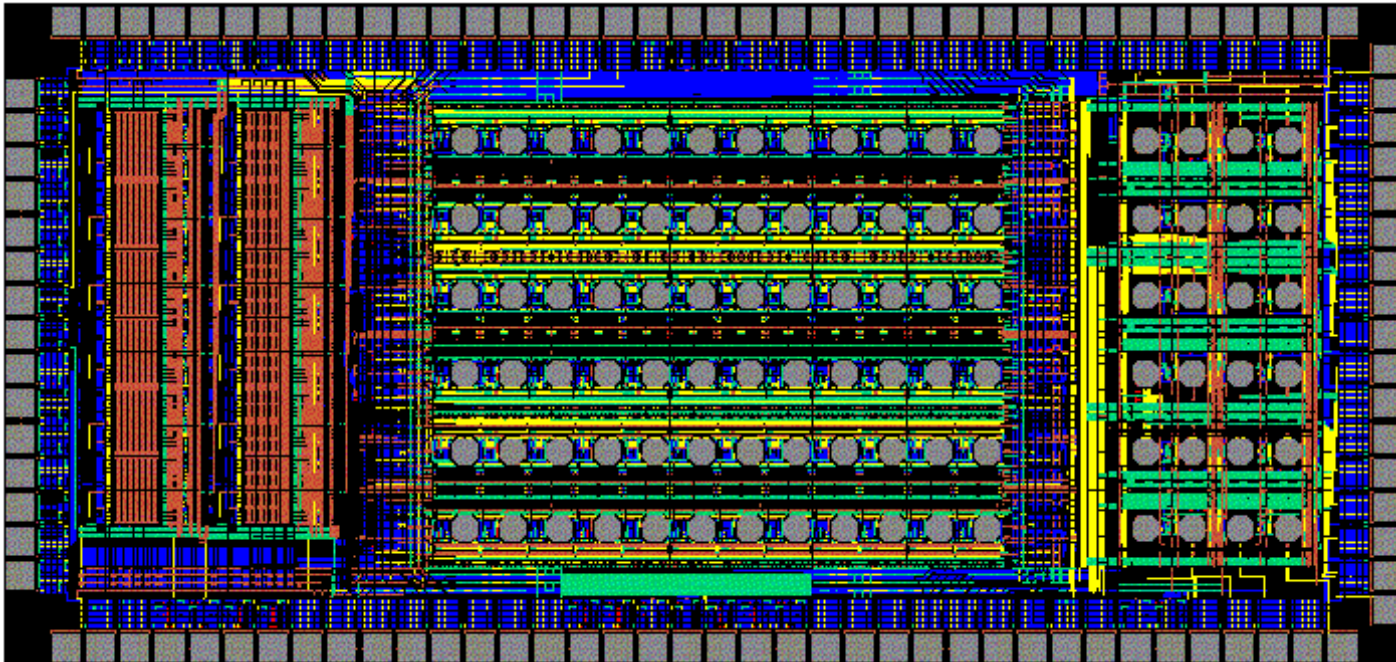
Irradiation Facility

- 60 keV X-Ray
 - 100-250krad/h (depending on distance), calibrated setup
- Institut für experimentelle Kernphysik, University of Karlsruhe
 - Thanks to Dr. Simonis, Mr. Dierlamm and Mr. Ritter for the help

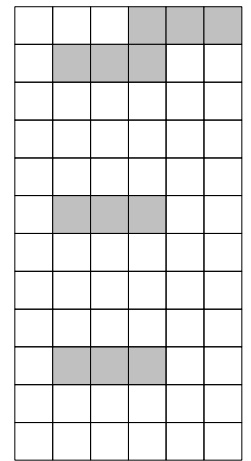


DCD2 Irradiation

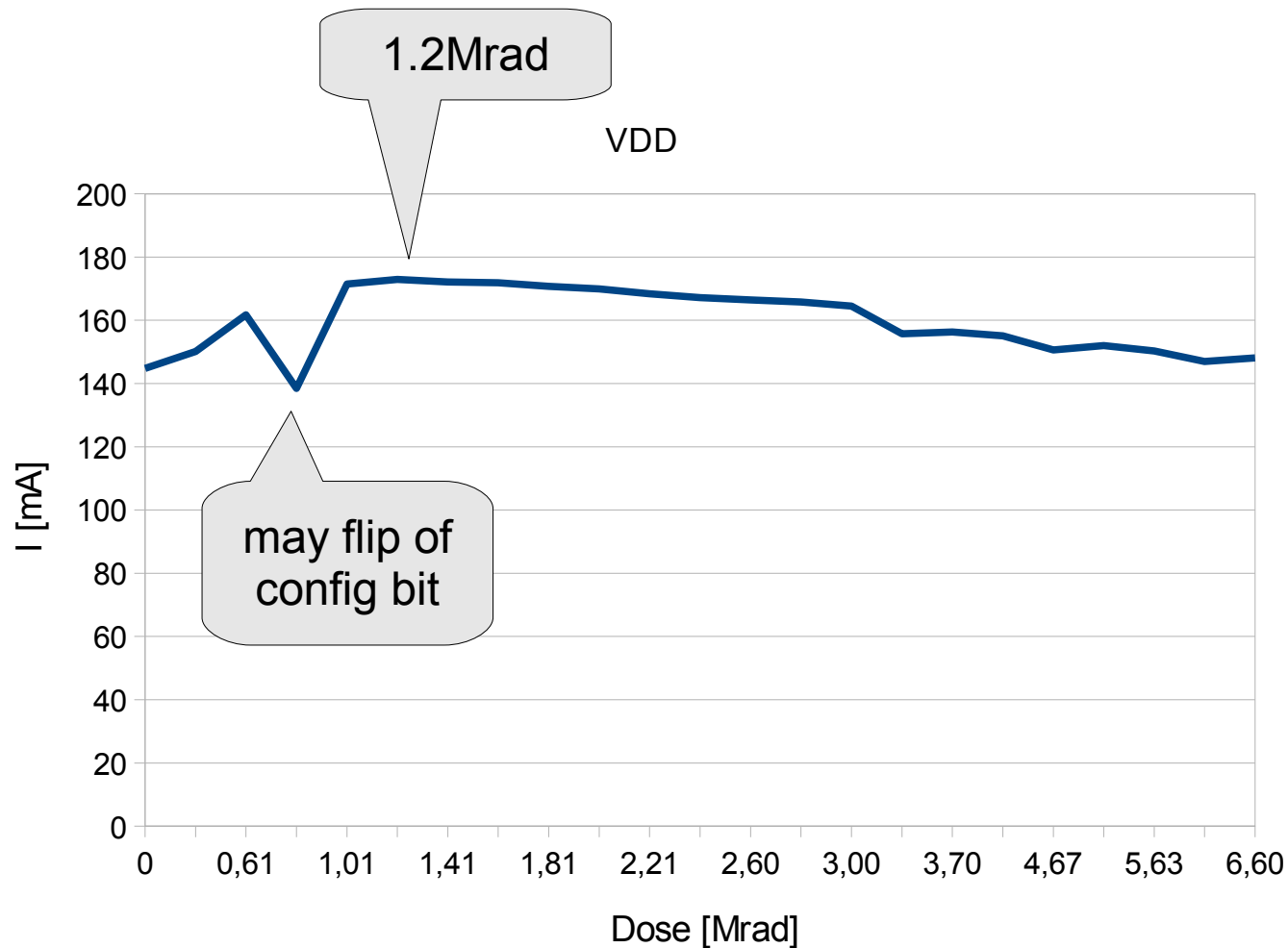
- test chip for new readout design
- UMC 0.18 μ m technology
- 72 inputs, each with:
 - a regulated cascode
 - two current memory cells for pedestal subtraction
 - two 8bit algorithmic ADCs
- high speed LVDS outputs



- Dose
 - 31h @99.5 krad/h (d=180mm) = 3.1 Mrad
 - 18h @241 krad/h (d=100mm) = 4.4 Mrad
 - Total = 7.5 Mrad
- DCD Operation Mode
 - clock running permanently
 - control registers loaded every 30s with default values
- Measurements (during irradiation):
 - current consumption on VDD
 - on selected pixels
 - ADC characteristics
 - Current memory cell operating range
 - Test injection current value

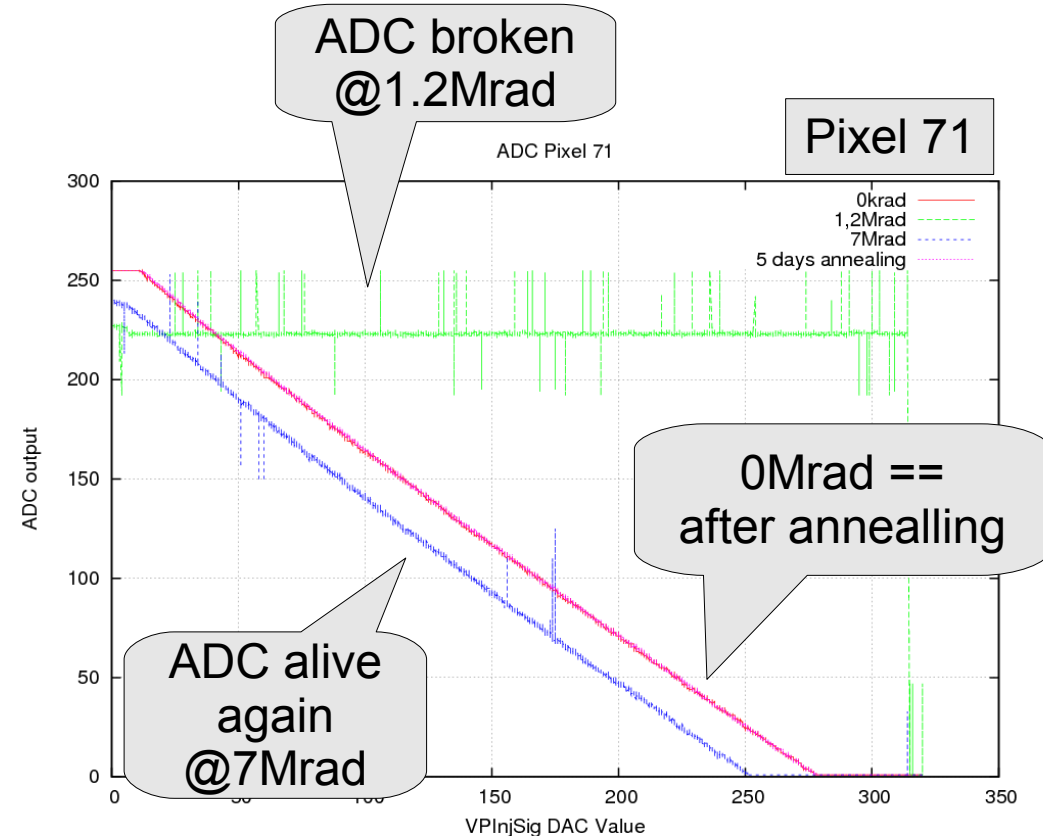
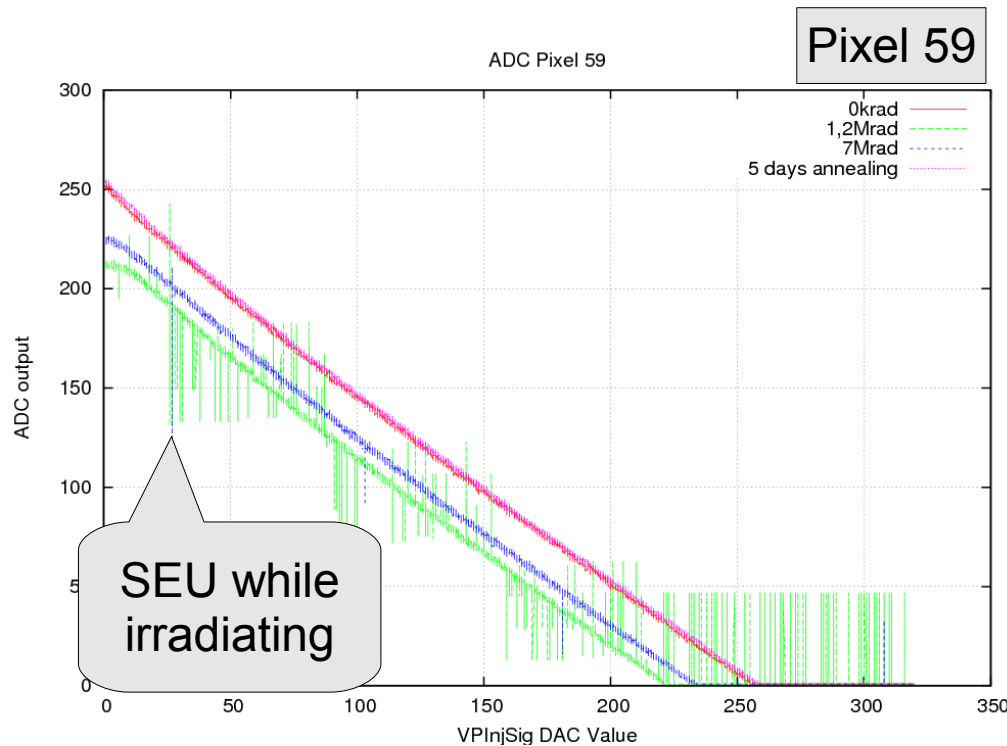


Current Consumption



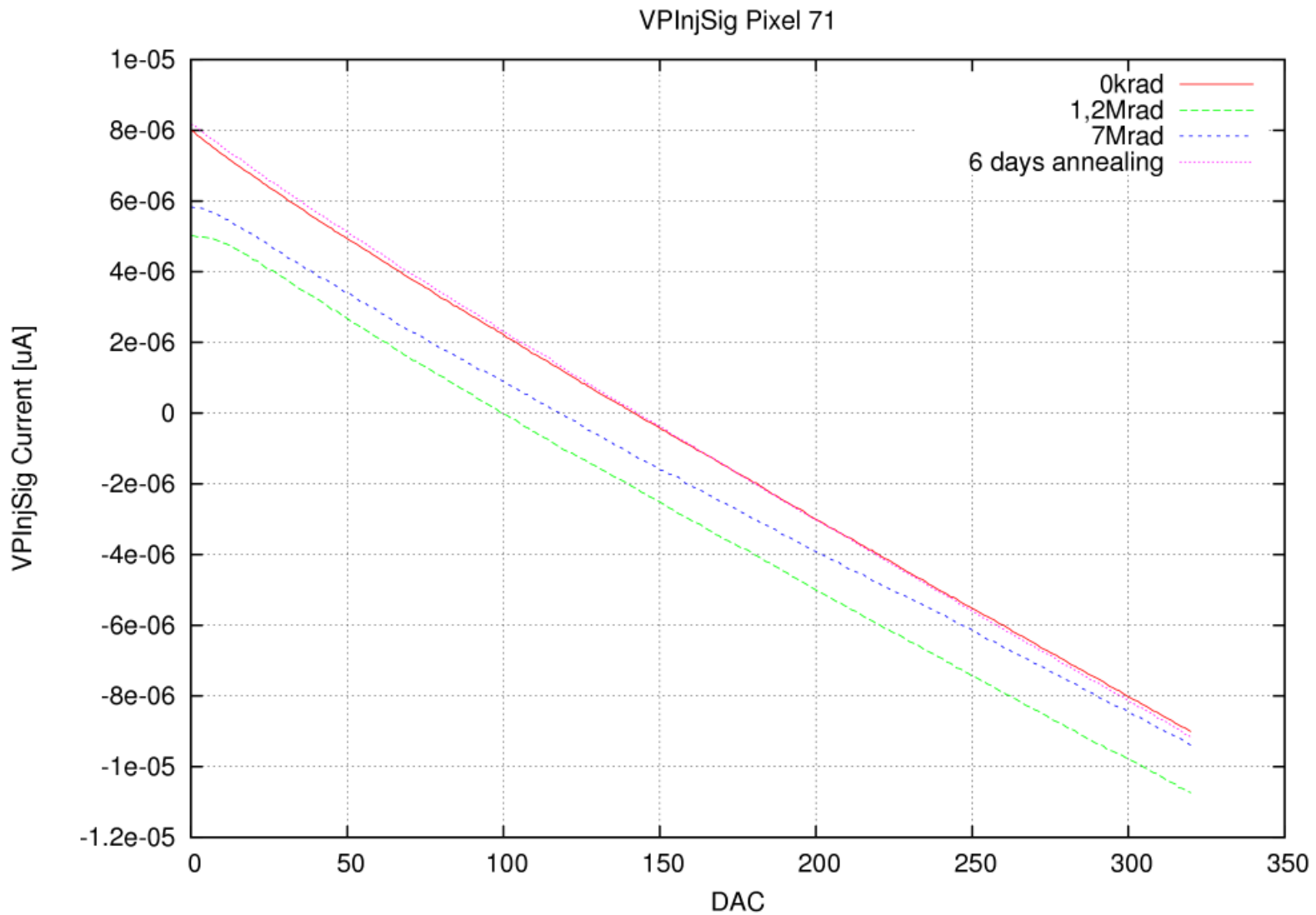
- VDD Current rises until 1.2Mrad
- then settles to pre-irradiation value

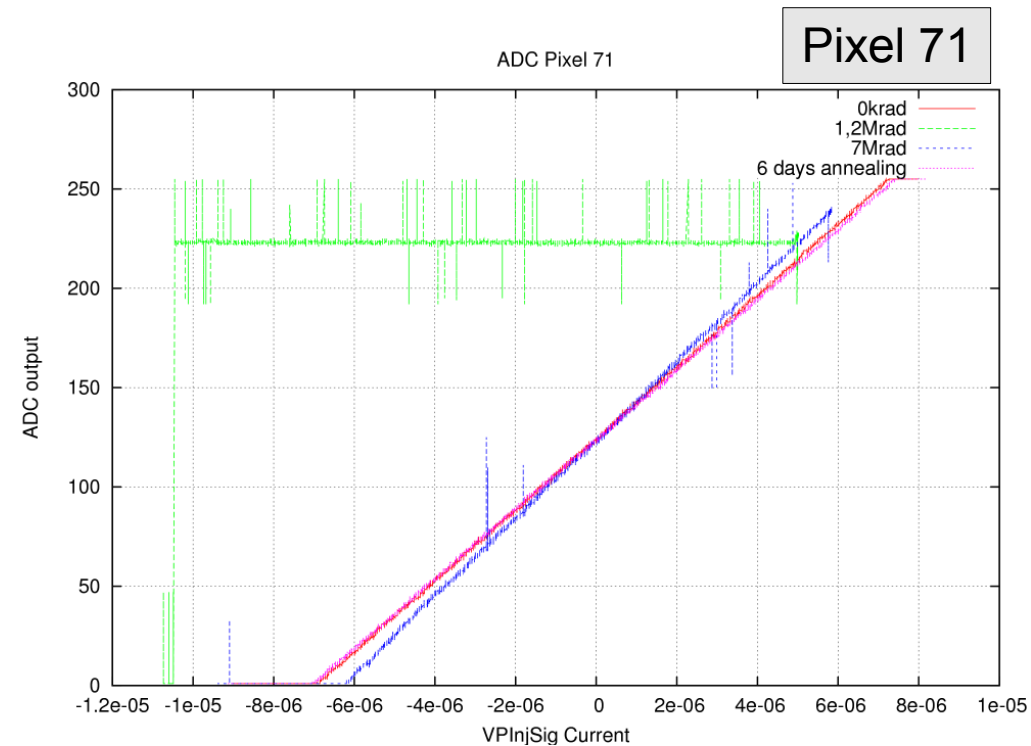
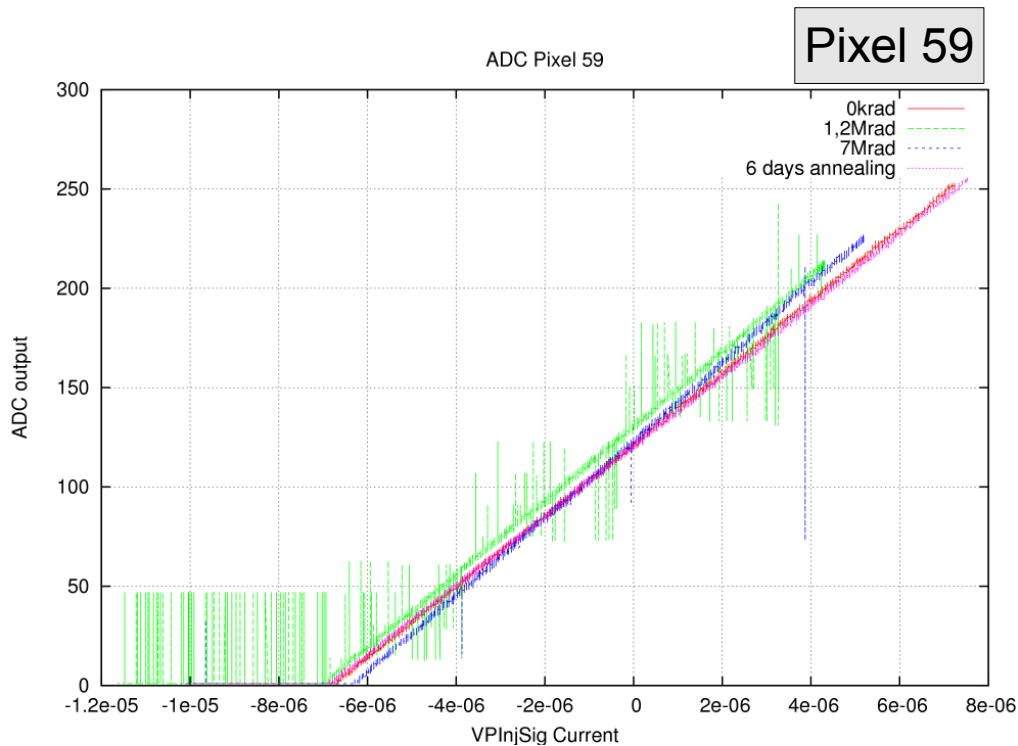
ADC: output code vs. test injection DAC



- SEU while irradiating (more at 1.2Mrad than at other dose)
- most radiation effects for <1.2Mrad
- >1.2Mrad : effects recover
- after 7Mrad and 6 days annealing: back to pre-irradiation behavior

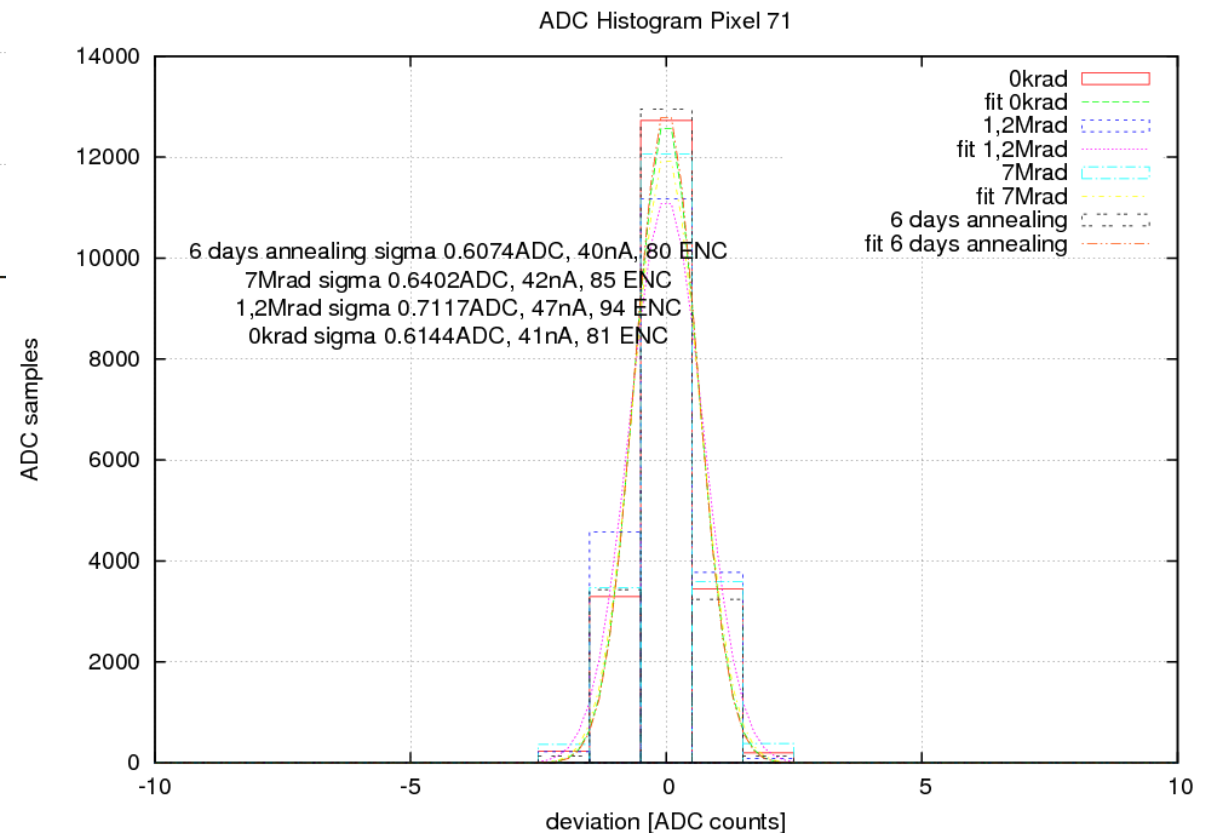
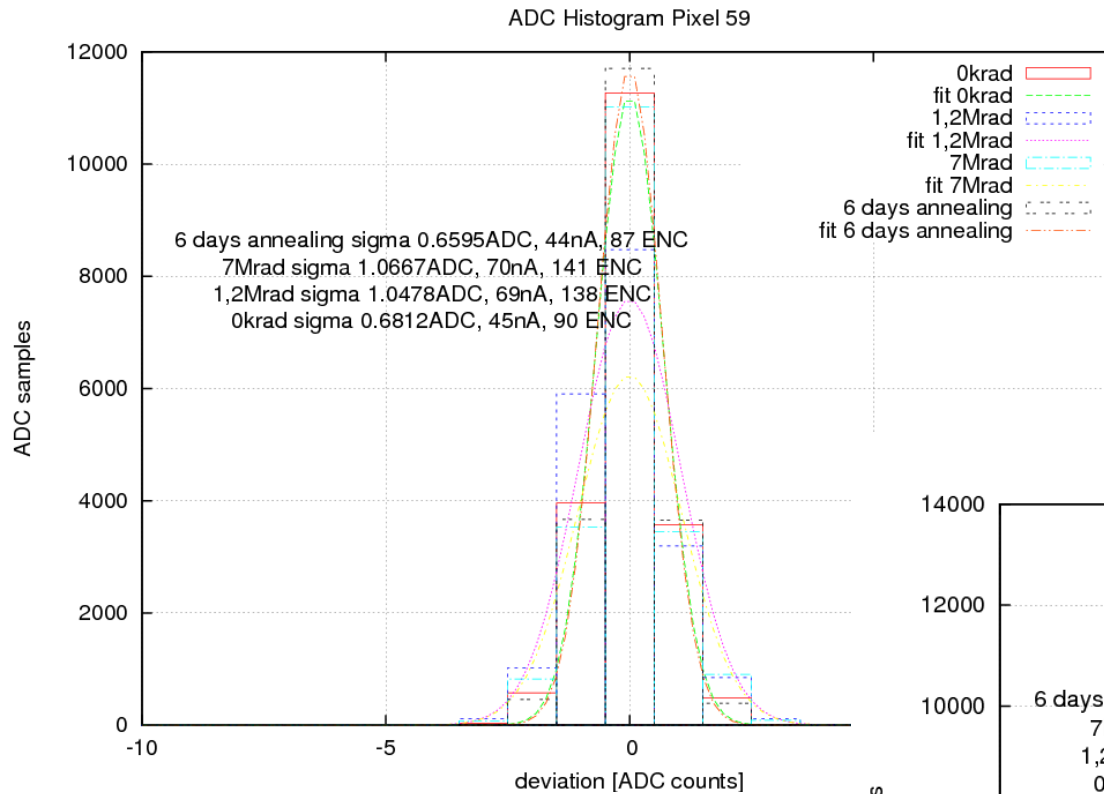
Test Injection Current vs. DAC value



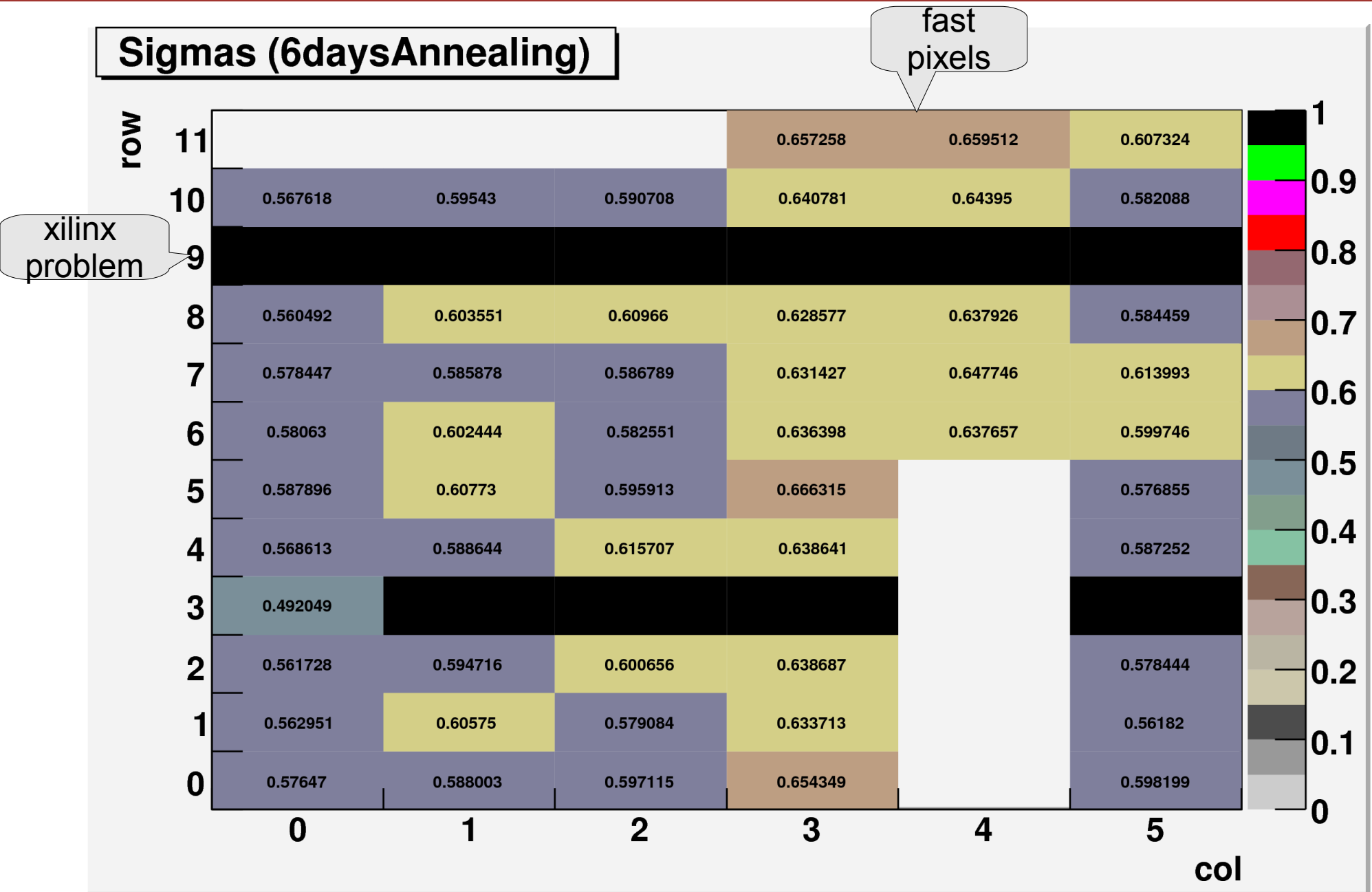


- plotted against the measured injection current
- shift in ADC characteristics mainly caused by shift in inj. current

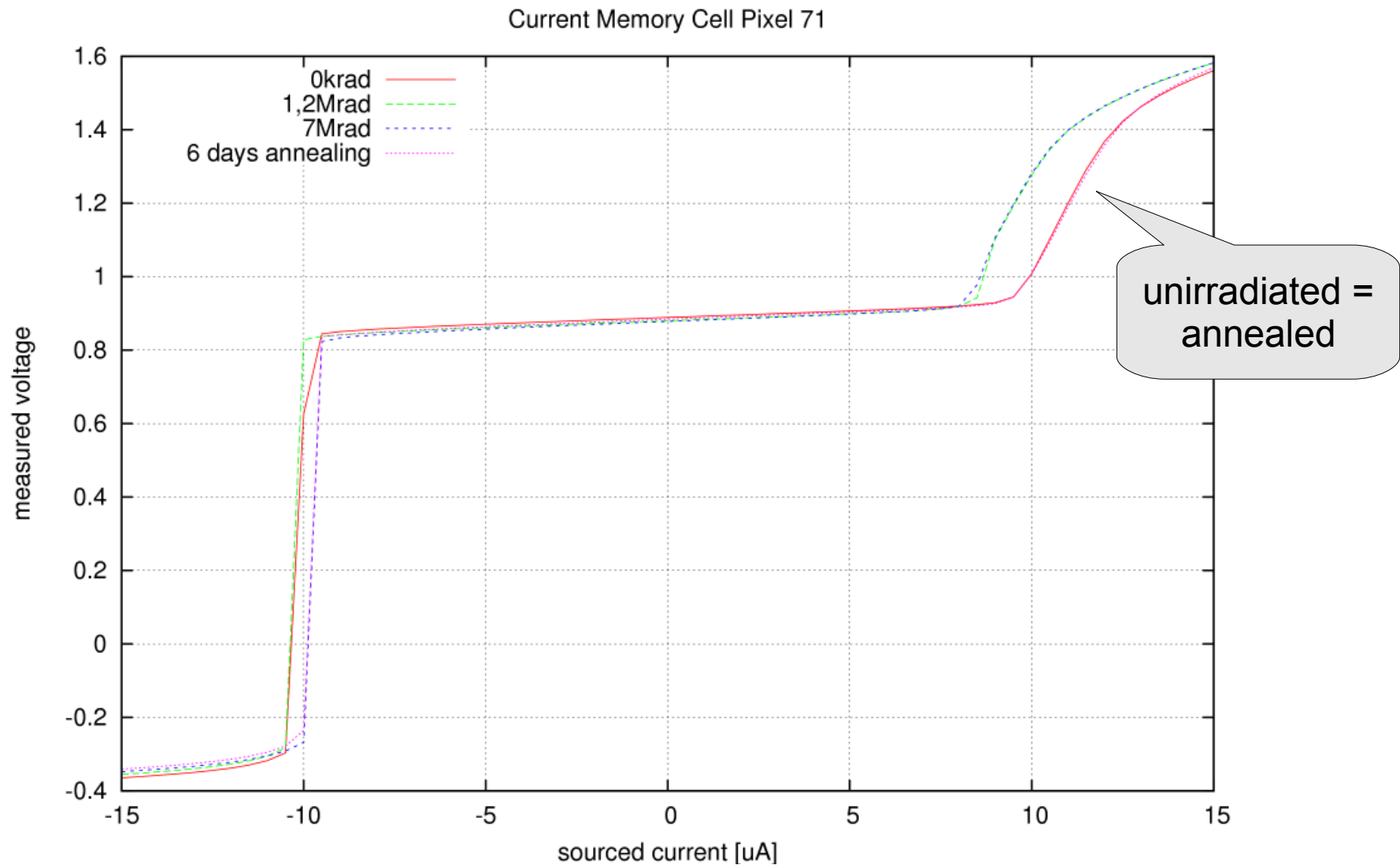
ADC Histogram



ADC Histogram Map



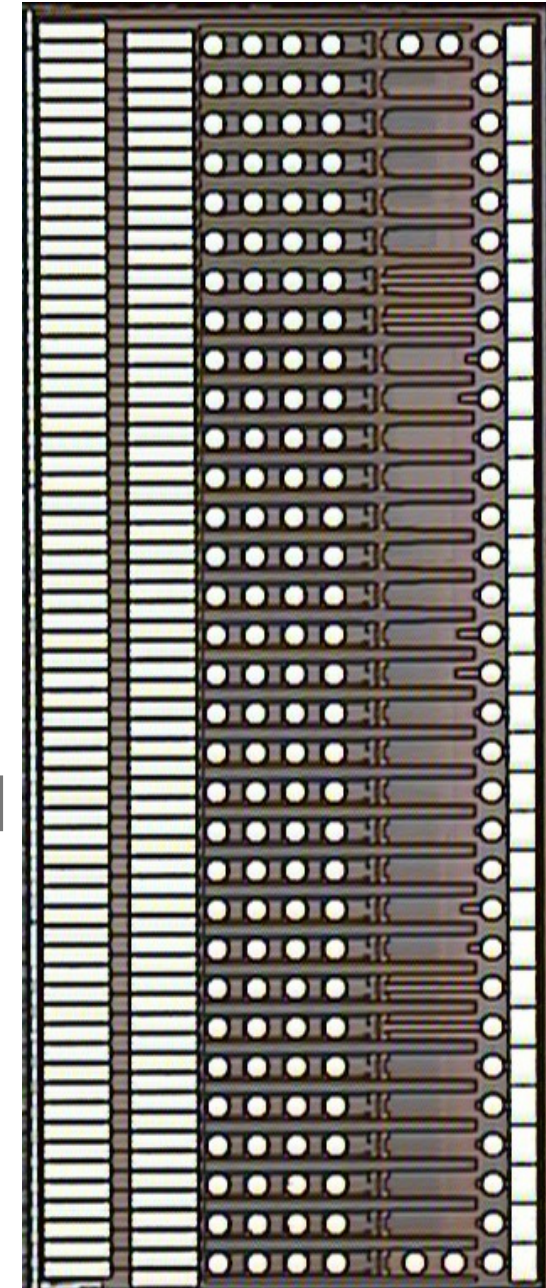
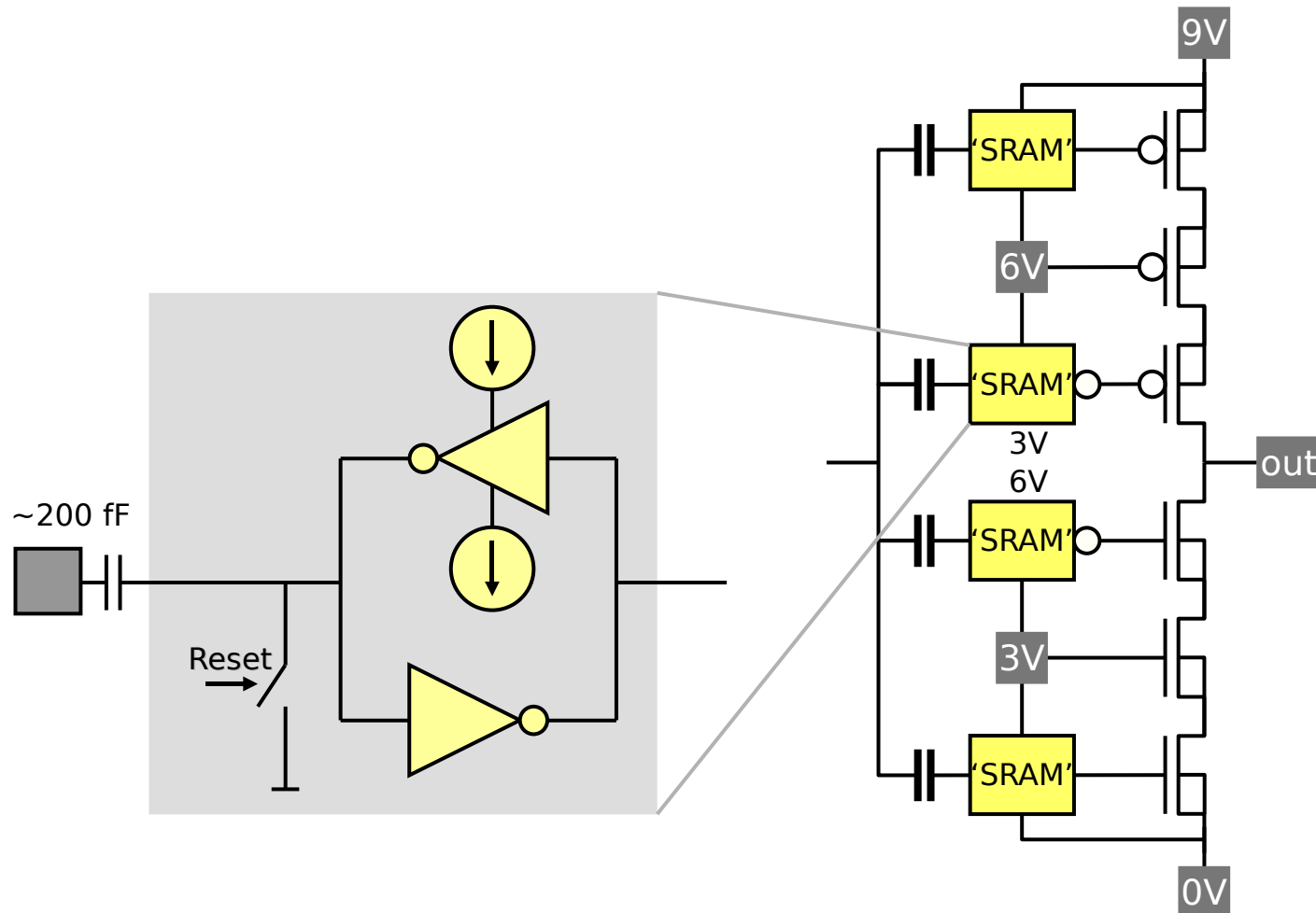
Current Memory Cells



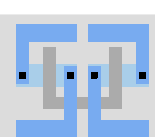
Switcher3 Irradiation

Cap Coupling

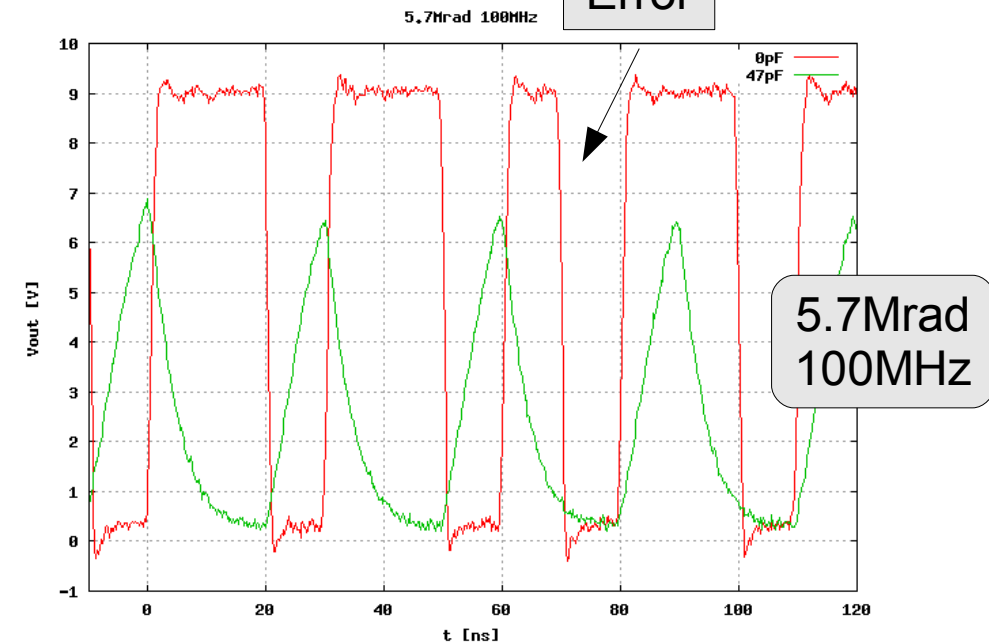
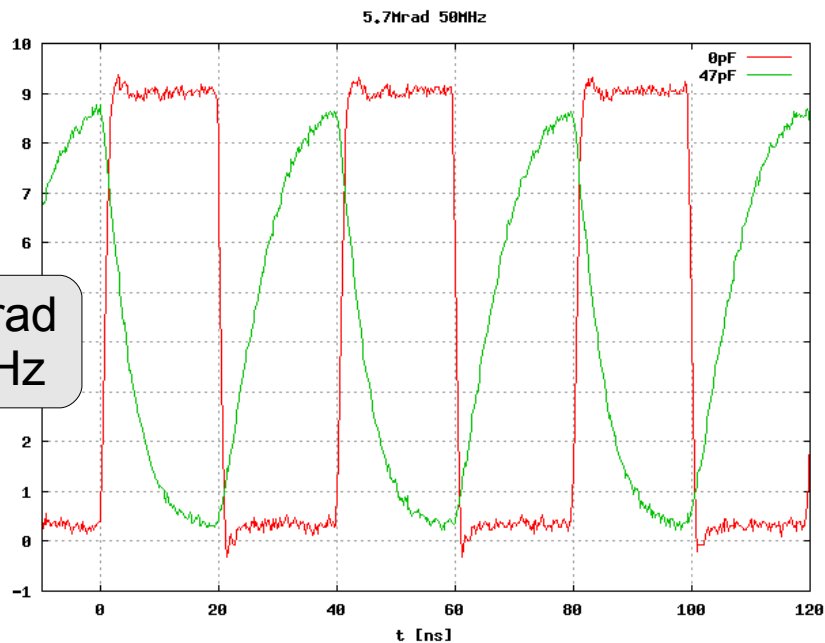
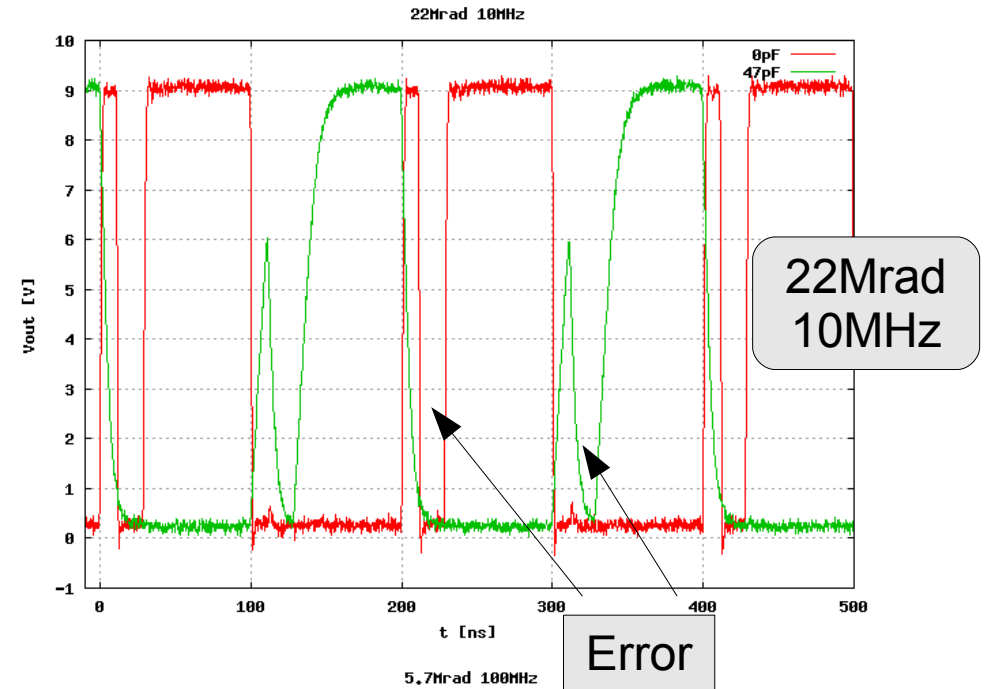
- 9V switching using three stacked 3.3V transistors
- AMS 0.35 μm twin well technology



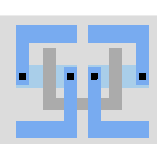
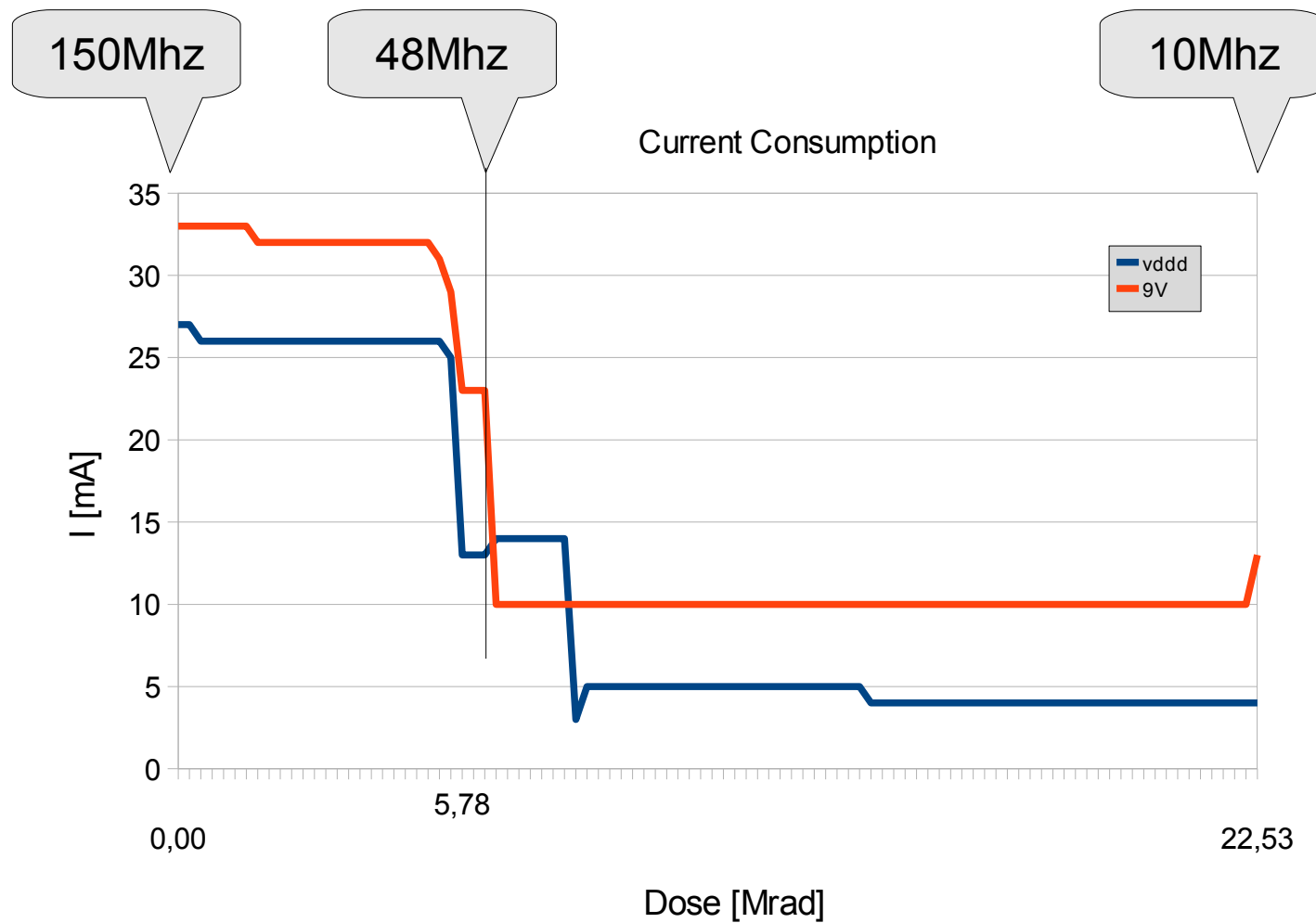
- Dose
 - 93.5h @241 krad/h = 22.5 Mrad
- Switcher Operation Mode
 - sequencer running (switching between 0pF and 47pF)
 - default register values loaded
- Measurements
 - current consumption of chip on VDD and 9V
 - rise times



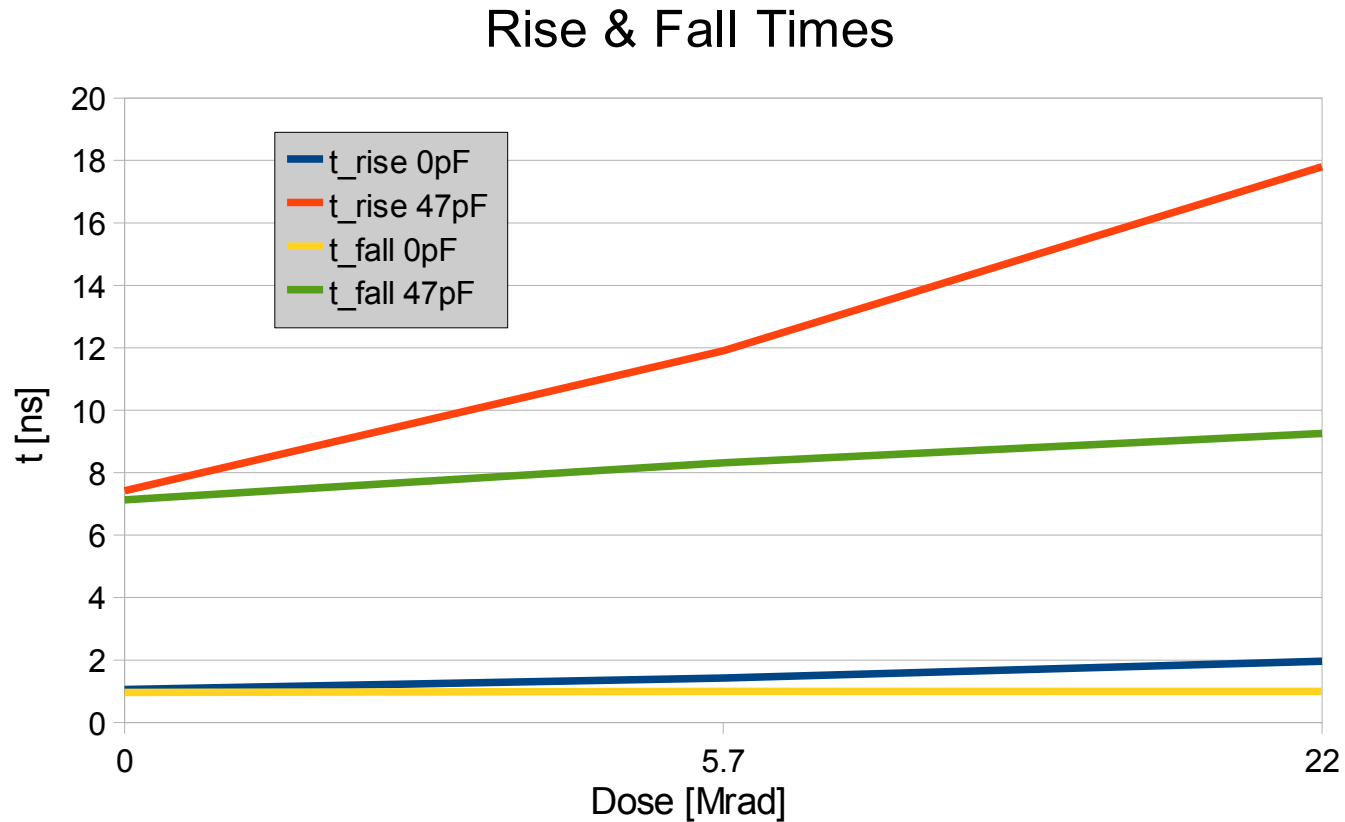
- 0Mrad $\rightarrow$ 150MHz
- 5.7Mrad $\rightarrow$ 50MHz
- 22Mrad $\rightarrow$ <10MHz



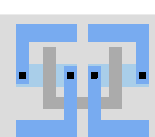
Current Consumption



- 9V output
- Oscilloscope reading



- DCD2
 - most effects saturate at 1.2Mrad
 - vdd increase by 14%
 - noise increase by 7%
 - all values back to pre-radiation after 6days annealing!
 - strange effects:
 - many corrupted ADC values at 1.2Mrad
 - some ADCs are dead at 1.2Mrad and recover with higher dose
- Switcher3
 - running after 5.7Mrad
 - risetimes double (7ns $\rightarrow$ 12ns)
 - after 22Mrad:
 - still errors at 10MHz $\rightarrow$ chip dead



- USB readout setups make irradiation easy
- flexible access to Karlsruhe facility
- very good support from staff!
- short distance between Mannheim and Karlsruhe is convenient
- stable beam during weekend allows high doses

Thank you!